

INFNSTUDIED ONSMATERIALS ROMA FOR the MUON COLLIDER Sezione di Roma

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MUON COLLIDER AT a GLANCE

Many key challenges to face:

- Dense neutrino flux
- Beam-induced background
- Cost & power consumption limiting energy reach and beam quality
- Muon production and cooling drives beam quality and achievable luminosity







LIGHT-MATERIAL ABSORBERS FOR MUON COOLING



- Low-Z and thin absorbers (LiH, H₂,...) to minimize beam Multiple Scattering
- Thin windows to contain liquid absorbers (Be, Si₃N₄, SiC, C

Parameters: > 20 to 5 MeV cooling > 4e12 muons/pulse > 5 Hz repetition rate > σ_{RMS}=0.6 mm







Absorber Material Characterisation

Target crash test with photons

lens

Absorber

Ex ante ex post characterisation

mirror

Nd:YAG laser

Wavelength: 1064 mm Laser output pulse E: 0.69 J Peak power: 0.35 GW Average power: 6900 mW Pulse rep. frequency: 10 Hz Pulse width: 5.7 ns

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Infrared Camera FLIR X6901sc SLS Optic: 17 mm, calibrated in the range [-80 °C, +300 °C]





vacuum chambers for thermal measurements





- determined through photothermal radiometry





IRRADIATION tests **ON** PARTICLE BEAMS







Validation of model predictions for thermal and mechanical behaviour of materials

DEPTH PROFILING by Photothermal Radiometry





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EXAMPLE of STRATIGRAPHY Studies

A New Device for High-Accuracy Measurements of the Hardness Depth Profile in Steels R. Li Voti, G. Leahu, C. Sibilla





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Stratigraphy of thermal diffusivity and hardness of steels

SURFACE ANALYSIS at ROMA TRE

Stilus Profilometer

- z resolution < 1 nm
- Large area analysis (stitching)



Fourier Transform - IR spectrometer

- Study between 100 cm⁻¹ and 2700 cm⁻¹
- Equipped with microscope
- Molecular analysis
- Functional group determination



Ref. Publications

FT-IR: Exploring Manufacturing Process and Degradation Products of Gilt and Painted Leather, M. Iorio et al., Appl. Sci. 2019 9(15), 3016 ToF-SIMS: Three-dimensional characterisation of OTFT on modified hydrophobic flexible polymeric substrate by low energy Cs+ io sputtering, L. Tortora et. al., Appl. Surf. Science 448 (2018) 628







Low-energy ion beam analysis (ToF-SIMS)

- Three particle guns: Bi+ 30 keV, Cs+ 0.2-11 keV, electron floodgun (20 V)
- Mapping with a lateral resolution < 100 nm
- Depth profiling < 1 nm</p>
- detector range: 1 a.m.u. 15000 a.m.u.
- e detector Time-of-Flight
- Limit of detection ~ ppm











thin Graphite target properties

Graphite HPG59 target sample, tested before and after thermal stress cycling



Detailed profilometry







Surface analysis through ToF-SIMS technique allows to evaluate the composition and impurities variations before and after thermal stress in different target regions









